D²PAK (TO-263)



21NK50Z-VB Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V_{DS} (V) at T_J max.	650				
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q _g max. (nC)	106				
Q _{gs} (nC)	14				
Q _{gd} (nC)	33				
Configuration	Single				

D

S N-Channel MOSFET

FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qq
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing
- ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS ($T_c = 25 \degree C$, unless otherwise noted)								
PARAMETER			SYMBOL	LIMIT	UNIT			
Drain-Source Voltage			V _{DS}	650	V			
Gate-Source Voltage			V _{GS}	± 30				
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$		20				
	VGS at 10 V	T _C = 100 °C	ID	13	A			
Pulsed Drain Current ^a			I _{DM}	60				
Linear Derating Factor				1.7	W/°C			
Single Pulse Avalanche Energy ^b			E _{AS}	367	mJ			
Maximum Power Dissipation			PD	208	W			
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C			
Drain-Source Voltage Slope	$T_J = T_J$	T _J = 125 °C		37	V/ns			
Reverse Diode dV/dt ^d			dV/dt	31	v/ns			
Soldering Recommendations (Peak Temperature)	c for	for 10 s		300	°C			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.



HALOGEN FREE



$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TYP. MAX. UNIT \\ \hline Maximum Junction-to-Case (Drain) R_{In,JA} - 0.5 & C.W \\ \hline Maximum Junction-to-Case (Drain) R_{In,JA} - 0.5 & C.W \\ \hline SPECIFICATIONS (T_J = 25 °C, unless otherwise noted) \\ \hline SPECIFICATIONS (T_J = 25 °C, unless otherwise noted) \\ \hline SPECIFICATIONS (T_J = 25 °C, unless otherwise noted) \\ \hline Satic & V_{OS} Temperature Coefficient AV_{OS}/T_J Reference to 25 °C, l_0 = 1 mA - 0.67 - V/C \\ \hline Case-Source Breakdown Voltage (N) V_{OS} V_{OS} = 0 V, l_0 = 250 \muA & 650 & V/C \\ \hline Case-Source Threshold Voltage (N) V_{OS} V_{OS} = 0 V, l_0 = 250 \muA & 2 & - & 4 & V \\ \hline Caste-Source Threshold Voltage (N) V_{OS} V_{OS} = 0 V & - & - & \pm 100 & nA \\ \hline V_{OS} Temperature Coefficient AV_{OS}/T_J Reference to 25 °C, l_0 = 1 mA - 0.67 & - & V/C \\ \hline Caste-Source Threshold Voltage (N) V_{OS} V_{OS} = 0 V & - & - & \pm 100 & nA \\ \hline V_{OS} Temperature Coefficient I & AV_{OS}/T_J Reference to 25 °C, l_0 = 1 mA - 0.67 & - & V/C \\ \hline Caste-Source Threshold Voltage (N) V_{OS} = 0 V V & V_{OS} = 0 V & - & - & \pm 100 & nA \\ \hline V_{OS} Temperature Coefficient I & Ioss & V_{OS} = 0 V V & I_0 = 11A & - & 7.0 & - & S \\ \hline Drain-Source On-State Resistance & R_{DB(ori)} V_{OS} = 500 V, V_{OS} = 0 V, I_0 = 11A & - & 7.0 & - & S \\ \hline Drain-Source On-State Resistance & C_{res} & V_{OS} = 0 V, V_{OS} = 0 V V & - & 0.4 & - & \\ \hline Total Gate Charge & Q_{git} & V_{OS} = 10 V & V_{OS} = 520 V, I_0 = 11 A & - & 7.0 & - & S \\ \hline Total Gate Charge & Q_{git} & V_{OS} = 10 V, V_{OS} = 0 V, V_{OS} = 0 V & - & 11 & 4 & - & \\ \hline Tatm-On Delay Time & I_{daton} & V_{OS} = 10 V & V_{OS} = 520 V, I_0 = 11 A & - & 2.2 & 44 \\ \hline Tatm-On Delay Time & I_{daton} & V_{OS} = 10 V, V_{S} = 0 V, V_{S} = 10 V & - & 2.4 & 4. \\ \hline Tatm-On Delay Time & I_{daton} & V_{OS} = 10 V, V_{S} = 0 V, V_{S} = 10 V & - & 0.4 & 4. \\ \hline Tatm-On Delay Time & I_{daton} & V_{OS} = 10 V, V_{S} = 10 V, $	THERMAL RESISTANCE RAT	NGS									
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP. MAX.			UNIT					
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R _{thJA}	- 62				°0.00				
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$$$ The state of the state $	Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.5				- °C/W				
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$$$ The state of the state $											
$ \begin{array}{ c c c c c c } \hline Static & & & & & & & & & & & & & & & & & & &$	SPECIFICATIONS (T _J = 25 °C, unless otherwise noted)										
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static	•	•						•		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D =	250 µA	650	-	-	V		
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	, I _D = 1 mA	-	0.67	-	V/°C		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Osta Osuma Laskara		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage	IGSS		$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Zara Cata Valtaga Drain Current	1	V _{DS} =	= 520 V, V _C	_{GS} = 0 V	-	-	1	μA		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	IDSS	V _{DS} = 520 \	/, V _{GS} = 0 ^v	V, T _J = 125 °C	-	-	500			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I	l _D = 11 A	-	0.19	-	Ω		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D	= 11 A	-	7.0	-	S		
$ \begin{array}{ c c c c c } \hline \text{Output Capacitance} & C_{oss} & V_{DS}^{C} = 100 V, \\ \hline \text{Reverse Transfer Capacitance} & C_{rss} & & & & & & & & & & & & & & & & & & $	Dynamic					-		-			
$ \begin{array}{ c c c c c c } \hline \text{Output Capacitance} & C_{oss} & V_{DS} = 100 \text{ V}, & - & 105 & - & - & 4 & - & - & - & 4 & - & - & -$	Input Capacitance	C _{iss}		V _{DS} = 100 V,		-	2322	-			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}				-	105	-			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		-	4	-				
$ \begin{array}{c c c c c c c c } \hline \mbox{Effective Output Capacitance, Time} & C_{o(tr)} & & & & & & & & & & & & & & & & & & &$		C _{o(er)}	N/ 01			-	84	-	pF		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C _{o(tr)}	$v_{DS} = 0 v to 520 v, v_{GS} = 0 v$		-	293	-				
$ \begin{tabular}{ c c c c c c c c c c } \hline Gate-Drain Charge & Q_{gd} & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 22 & 44 & $-$ & 34 & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 69 & $-$ & 0.9 & $-$ & 0.9 & $-$ & 0.9 & $-$ & 0.9 & $-$ & $-$ & 21 & $-$ & $-$ & 21 & $-$ & $-$ & 21 & $-$ & $-$ & $-$ & 53 & $-$ $	Total Gate Charge	Qg		V _{GS} = 10 V I _D = 11 A, V _{DS} = 520		-	71	106	nC		
$ \begin{tabular}{ c c c c c c c c c c } \hline Gate-Drain Charge & Q_{gd} & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 33 & $-$ & $-$ & 22 & 44 & $-$ & 34 & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 42 & 84 & $-$ & 68 & 102 & $-$ & 69 & $-$ & 0.9 & $-$ & 0.9 & $-$ & 0.9 & $-$ & 0.9 & $-$ & $-$ & 21 & $-$ & $-$ & 21 & $-$ & $-$ & 21 & $-$ & $-$ & $-$ & 53 & $-$ $	Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$			-	14	-			
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge					-	33	-	1		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-On Delay Time					-	22	44			
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r	V _{DD} =	V _{DD} = 520 V, I _D = 11 A,		-	34	68	1		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-Off Delay Time	t _{d(off)}			-	68	102	115			
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMIsMT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V-0.91.2VDiode Forward VoltageV_{SDT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V-0.91.2VReverse Recovery TimetrrT_J = 25 °C, I_F = I_S = 11 A, dl/dt = 100 A/µs, V_B = 25 V-160-ns	Fall Time				-	42	84				
	Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Body Diode Characteristi	cs									
Pulsed Diode Forward CurrentIsmIntegra reverse p - n junction diode53Diode Forward Voltage V_{SD} $T_J = 25 ^{\circ}C, I_S = 11 A, V_{GS} = 0 V$ -0.91.2VReverse Recovery Time t_{rr} $T_J = 25 ^{\circ}C, I_F = I_S = 11 A, dl/dt = 100 A/\mu s, V_B = 25 V$ -160-ns	Continuous Source-Drain Diode Current	١ _S	,	1 ^D		-	-	21			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Pulsed Diode Forward Current	I _{SM}			-	-	53	A			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V			
Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 11 \ A$, $dI/dt = 100 \ A/\mu s$, $V_B = 25 \ V$ -1.2- μC			T _J = 25 °C, I _F = I _S = 11 A,		-	-		ns			
$di/dl = 100 \text{ Av} \mu \text{s}, v_{\text{B}} = 25 \text{ V}$	-				-		-				
					-	14	-				

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

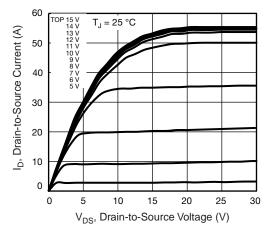


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

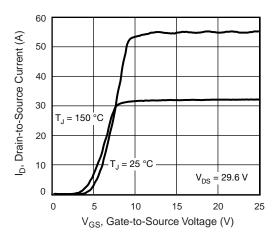


Fig. 3 - Typical Transfer Characteristics

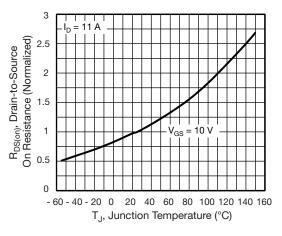


Fig. 4 - Normalized On-Resistance vs. Temperature

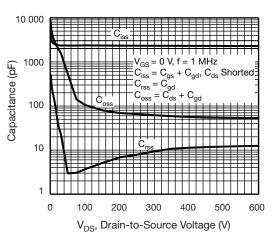


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}



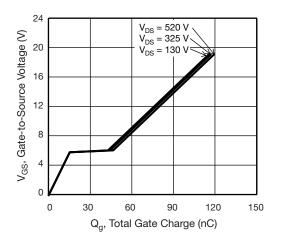


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

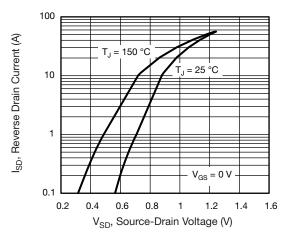


Fig. 8 - Typical Source-Drain Diode Forward Voltage

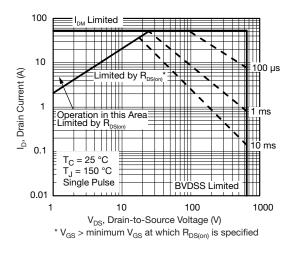


Fig. 9 - Maximum Safe Operating Area

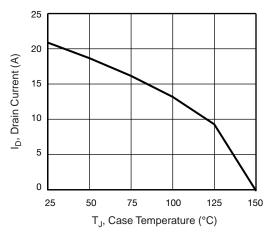


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage





Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

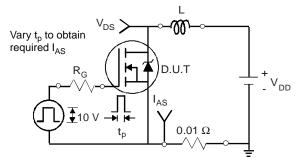


Fig. 15 - Unclamped Inductive Test Circuit

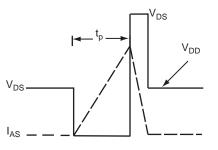


Fig. 16 - Unclamped Inductive Waveforms

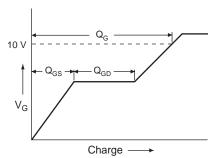
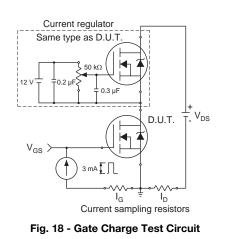
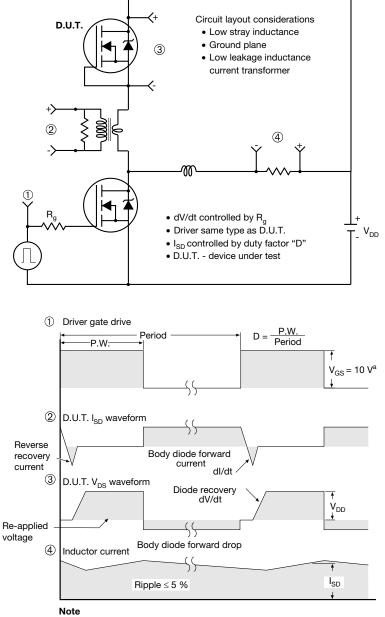


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

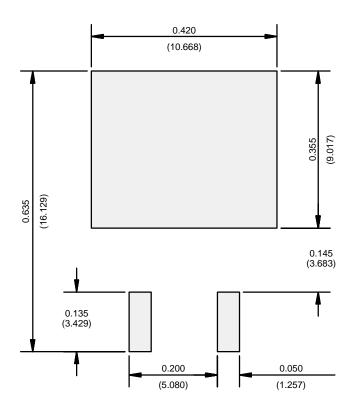


a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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